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INFORMATION DISCLOSURE

Substitute for form 1449/PTO

Sheet 1

STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Col	Complete if Known				
Application Number	1017731077				
Filing Date	February 5,2004				
First Named Inventor	Treado				
Art Unit	2877				
Examiner Name	. Lauch man, Layla b.				
Attorney Docket Number	030687				

	1 4			DOCUMENTS	
Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant
A	A -	Number-Kind Code ^{2 (d known)}	<u> </u>		Figures Appear
	A	^{US-} 5,194,912	03-16-1993	Batchelder et al.	
C	B	^{US-} 5,377,003	12-27-1994	Lewis et al.	
	U	^{US-} 5,377,004	12-27-94	Owen et al.	
Dec	P	^{US-} 5,442,438	08-15-1995	Batchelder et al.	
28	E	^{US-} 5,493,443	02-20-1996	Simon et al.	
Se	F	^{US-} 5,528,393	06-18-1996	Sharp et al.	
	6	^{US-} 5,623,342	04-22-1997	Baldwin et al.	
	H	^{US-} 5,689,333	11-18-1997	Batchelder et al.	
II.	I	^{US-} 5,710,626	01-20-1998	O'Rourke et al.	**************************************
	1	^{US-} 5,862,273	01-19-1999	Pelletier	
1	K	^{US-} 5,901,261	05-04-1999	Wach	
	L	^{US-} 5,911,017	06-08-1999	Wach et al.	
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X	N	us- 6,002,476	12-14-1999	Treado	
91	0	us- 6,088,100	07-11-2000	Brenan et al.	
Z	P	^{US-} 6,483,641	11-19-2002	MacAulay	
RI	0	^{US-} 6,571,117	05-27-2003	Marbach	
	R	^{US-} 6,300,618	10-09-2001	Tanaami et al.	
7	5	^{US-} 5,381,236	01-10-1995	Morgan	

		FORE	IGN PATENT DOCK	JMENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	T.
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\mathbf{X}_{-}	_1_	PCT/CA98/00092	08-13-1998	Raz et al.		Г
8	U	WO95/11624	05-1995	Feld et al.		r
8	V	EP 0174778 B1	11-30-88	Mumford		r
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	Application Number	. 10/773,077
INFORMATION DISCLOSURE	Filing Date	Feb 5, 2004
	First Named Inventor	Treado
STATEMENT BY APPLICANT	Art Unit	2877
(Use as many sheets as necessary)	Examiner Name	Lauchman, hayla 6,
neet 2 of . 9	Attorney Docket Number	030687

	1		U. S. PATEN	DOCUMENTS	
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R	2	^{US-} 6,530,882	03-11-2003	Farkas et al.	
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8	BB	^{US-} 6,181,414	01-30-2001	Raz et al.	
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Q_	EE	^{US-} 5,394,499	02-28-1995	Ono et al.	
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	66	^{US-} 5,974,211	10-26-1999	Slater	·
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(Use as many sheets as necessary)	Examiner Name	Lauchman, Layla G
Sheet 3 of . 4	Attorney Docket Number	1030687

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4	00	^{US-} 6,404,497	06-11-2002	Backman et al.	
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ZZ	55	^{US-} 3,806,257	04-23-1974	Amos	
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R	UЙ	^{US-} 4,802,760	02-07-1989	Inoue et al.	
R	٧V	^{US-} 2004/0004715	01-08-2004	Tuschel et al.	
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1	Substitute for form 1449/PTO		Complete if Known
	Application Number :/0/773,077 FILING Date Filling Date Followay 5, 2004 First Named Inventor Treado Art Unit :2877 Examiner Name !Lauchman, hayla G,		
	INFORMATION DISCLOSURE	Filing Date	. February 5, 2004
	STATEMENT BY APPLICANT	First Named Inventor	
l	(Use as many sheets as necessary)	Art Unit	2877
L		Examiner Name	! Lavchman, hayla G.
/	Sheet 4 of	Application Number :/0/773,077 CLOSURE Filing Date Followary 5, 2004 PPLICANT First Named Inventor Treado Art Unit :2877 Examiner Name ! Lauchman, hayla G.	

:		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
80	WW	SKINNER et al. "Remote Raman Microimaging Using An AOTF and a Spartially Coherent Microfiber Optical Probe," Applied Spectroscopy, Vol. 50 No. 8, (1996) pp.1007-1014.	
8	**	I. LEWIS AND P. GRIFFITHS, "Raman Spectrometry with Fiber-Optic Sampling," Applied Spectroscopy, Vol. 50, No. 10, (1996) pp. 12A-29A.	
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B		Characterization of Semiconductors III (1986) pp. 26-34.	
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Examiner Date Signature Considered

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Substitute for form 1445				Complete if Known	
			Application Number	10/773,077	
INFORMAT				February 5, 2004	
STATEMEN	IT BY AF	PPLICAN	First Named Inventor	Treado	
(Use as ma	nny sheets as nec	cessarv)	Art Unit	2877	
,			Examiner Name	. Lauch man, Layla G.	
Sheet 5	of	- 8	Attorney Docket Number	030687	

		NON PATENT LITERATURE DOCUMENTS	
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Examiner	Date	<u> </u>
Signature	Considered	
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				Examiner Name	Lauchman, Layla G.	
Sheet	6	of	·· 8	Attorney Docket Number	030687	

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\$	N'	NAKASHIMA et al., "Raman Microprobe Study of Recrystallization in lon-Implanted and Laser-Annealed Polycrystalline Silicon," Journal of	
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Sheet 7 of 7	Attorney Docket Number	1030687		

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Examiner Initials*	Cite No.1		
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Substitute for form 1449/PTO		Application Number	10/773,077			
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		First Named Inventor	Treado			
	(Use as many a	.b		Art Unit	2877	
	(USS ES MENY E	eneggi es n	ocessery)	Examiner Name	Lauchman, Layla G.	
Sheet	a	of	8	Attorney Docket Number	1030687	

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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Date Examiner Considered Signature

"EXAMINER: Initial if reference considered, whether expot citation is in conformance with MPEP 609. Draw line through citation if for in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (options). 2 Applicant is to place a check mark here if English language Translation is attached.

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